MSKSEMI 美森科













ESD

3

TSS

MOV

GDT

 PLED

FDD5614P

Product specification





General Description

These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

BVDSS	RDSON	ID
-60V	75mΩ	-15A

Features

- -60V,-15A, RDS(ON) = $75m\Omega$ @VGS = -10V
- Improved dv/dt capability
- Fast switching
- 100% EAS Guaranteed
- Green Device Available

Applications

- Motor Drive
- Power Tools
- LED Lighting

Reference News

PACKAGE OUTLINE	P-Channel MOSFET	Marking
TO-252	D ° S	MSKSEMI FDD5614P

Absolute Maximum Ratings (TC=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-60	V
Vgs	Gate-Source Voltage	±20	V
	Drain Current - Continuous (Tc=25℃)	-15	Α
lD	Drain Current - Continuous (Tc=100℃)	-11	Α
Ірм	Drain Current - Pulsed¹	-45	Α
Po	Power Dissipation (Tc=25℃)	40	W
PD	Power Dissipation - Derate above 25°C	0.16	W/℃
Тѕтс	Storage Temperature Range	-55 to 150	$^{\circ}$
TJ	Operating Junction Temperature Range	-55 to 150	$^{\circ}$

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
RеJA	Thermal Resistance Junction to ambient		62	°C/W
Rелс	Thermal Resistance Junction to Case		6.1	°C/W



Electrical Characteristics (T_J=25 ℃, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=-250uA	-60			V
△BVpss/△TJ	BVpss Temperature Coefficient	Reference to 25℃, I _D =-1mA		-0.05		V/℃
lana	Drain-Source Leakage Current	V _{DS} =-60V , V _{GS} =0V , T _J =25℃			-1	uA
IDSS	Brain-Source Leakage Guirent	V _{DS} =-48V , V _{GS} =0V , T _J =125℃			-10	uA
Igss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA

On Characteristics

RDS(ON)	Static Drain-Source On-Resistance	Vgs=-10V , ID=-5A		75	100	mΩ
1 450(014)	State Brain Source Ciri todictaines	V _G s=-4.5V , I _D =-4A		100	130	mΩ
V _{GS(th)}	Gate Threshold Voltage	-Vgs=Vps , Ip=-250uA	-1.0	-1.6	-2.5	V
$^{\triangle}V$ GS(th)	V _{GS(th)} Temperature Coefficient	VG3-VD3 , ID2000A		5		mV/°C
gfs	Forward Transconductance	V _{DS} =-10V , I _D =-6A		8.5		S

Dynamic and switching Characteristics

Dynamic a	nd switching Characteristics				
Qg	Total Gate Charge ^{3,4}		 16.4		
Qgs	Gate-Source Charge ^{3,4}	V _{DS} =-30V , V _{GS} =-10V , I _D =-6A	 2.8		nC
Qgd	Gate-Drain Charge ^{3, 4}		 3.6		
Td(on)	Turn-On Delay Time ^{3,4}		 8.3		
Tr	Rise Time ^{3 , 4}	VDD=-30V , VGS=-10V ,	 29.6		no
T _{d(off)}	Turn-Off Delay Time ^{3,4}	R _G =6Ω l _D =-1A	 51.7		ns
Tf	Fall Time ^{3, 4}		 15.6		
Ciss	Input Capacitance		 870	-	
Coss	Output Capacitance	V _{DS} =-30V , V _{GS} =0V , F=1MHz	 70		pF
Crss	Reverse Transfer Capacitance		 42		
Rg	Gate resistance	V _G s=0V, V _D s=0V, F=1MHz	 16		Ω

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
l s	Continuous Source Current	V _G =V _D =0V , Force Current			-15	Α
lsм	Pulsed Source Current	,			-30	Α
VsD	Diode Forward Voltage	Vgs=0V , Is=-1A , TJ=25℃			-1.2	V

Note:

^{1.}Repetitive Rating: Pulsed width limited by maximum junction temperature.

 $^{2.}V_{DD} = 25V, V_{GS} = 10V, L = 0.1 mH, I_{AS} = 11A., R_G = 25\Omega, Starting~T_J = 25^{\circ}C.$

^{3.}The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.

^{4.} Essentially independent of operating temperature.

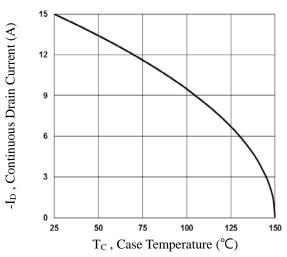


Fig.1 Continuous Drain Current vs. Tc

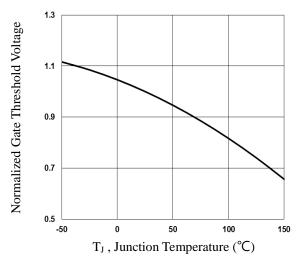


Fig.3 Normalized V_{th} vs. T_J

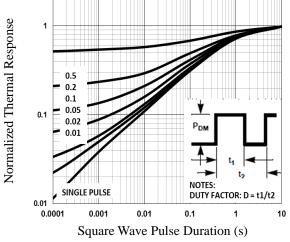


Fig.5 Normalized Transient Impedance

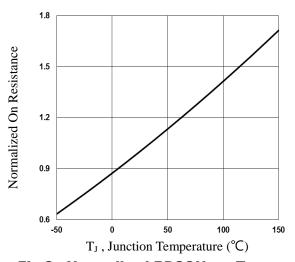


Fig.2 Normalized RDSON vs. TJ

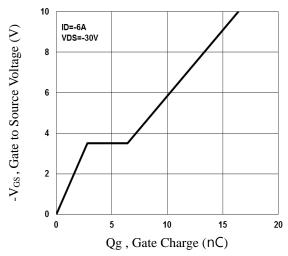


Fig.4 Gate Charge Waveform

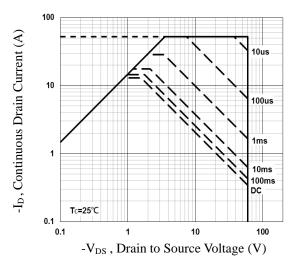


Fig.6 Maximum Safe Operation Area



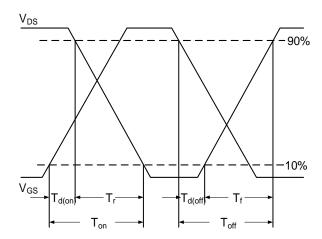
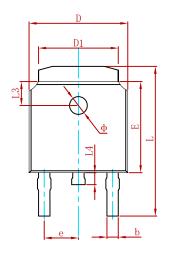
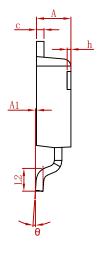


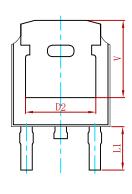
Fig.7 Switching Time Waveform



PACKAGE MECHANICAL DATA

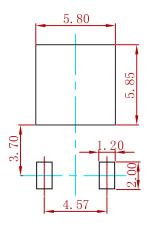






Cumbal	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190	REF.
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900	REF.	0.114	REF.
L2	1.400	1.700	0.055	0.067
L3	1.600	REF.	0.063	REF.
L4	0.600	1.000	0.024	0.039
Ф	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250	REF.	0.207	REF.

Suggested Pad Layout



- 1. Controlling dimension: in millimeters.
- 2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
FDD5614P	TO-252	2500



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